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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/717,403	11/19/2003	Patrick Y. Huet	58551.US	8656
*****	7590 12/27/200° NT CUSTOMER	EXAMINER		
C/O LUEDEK	A, NEELY & GRAHA	VALENTIN, JUAN D		
P.O. BOX 1871 KNOXVILLE,		ART UNIT	PAPER NUMBER	
			2877 ·	
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		•	NOTIFICATION DATE	DELIVERY MODE
			12/27/2007	ELECTRONIC

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Notice of the Office communication was sent electronically on above-indicated "Notification Date" to the following e-mail address(es):

RBARNES@LNG-PATENT.COM rick@thebarneshome.com

## Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)			
10/717,403	HUET ET AL.	HUET ET AL.		
Examiner	Art Unit			
Juan D. Valentin II	2877			

Before the Filing of an Appeal Brief	Examiner	Art Unit				
	Juan D. Valentin II	2877				
The MAILING DATE of this communication appe	ears on the cover sheet with the c	orrespondence add	ress			
THE REPLY FILED 12 December 2007 FAILS TO PLACE THIS		·				
<ol> <li>The reply was filed after a final rejection, but prior to or or this application, applicant must timely file one of the follow places the application in condition for allowance; (2) a Not a Request for Continued Examination (RCE) in compliant time periods:</li> <li>The period for reply expiresmonths from the mailing</li> </ol>	wing replies: (1) an amendment, aff otice of Appeal (with appeal fee) in o ce with 37 CFR 1.114. The reply mu	idavit, or other eviden compliance with 37 Cl	rce, which FR 41.31; or (3)			
b) The period for reply expires on: (1) the mailing date of this Advisory Action, or (2) the date set forth in the final rejection, whichever is later. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of the final rejection.  Examiner Note: If box 1 is checked, check either box (a) or (b). ONLY CHECK BOX (b) WHEN THE FIRST REPLY WAS FILED WITHIN						
TWO MONTHS OF THE FINAL REJECTION. See MPEP 7 Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of ex under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	on which the petition under 37 CFR 1.1 tension and the corresponding amount shortened statutory period for reply origing than three months after the mailing da	of the fee. The approprinally set in the final Office	ate extension fee ce action; or (2) as			
2: The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exte a Notice of Appeal has been filed, any reply must be filed AMENDMENTS	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of th	is of the date of e appeal. Since			
3. The proposed amendment(s) filed after a final rejection, but prior to the date of filing a brief, will <u>not</u> be entered because  (a) They raise new issues that would require further consideration and/or search (see NOTE below);  (b) They raise the issue of new matter (see NOTE below);						
(c) They are not deemed to place the application in be appeal; and/or (d) They present additional claims without canceling a	corresponding number of finally rej		he issues for			
NOTE: (See 37 CFR 1.116 and 41.33(a)). 4 The amendments are not in compliance with 37 CFR 1.1 5 Applicant's reply has overcome the following rejection(s)	21. See attached Notice of Non-Co	mpliant Amendment (	PTOL-324).			
<ol> <li>Newly proposed or amended claim(s) would be all non-allowable claim(s).</li> </ol>	,	·				
7.  For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is pro The status of the claim(s) is (or will be) as follows: Claim(s) allowed:		l be entered and an e	xplanation of			
Claim(s) allowed: Claim(s) objected to: Claim(s) rejected: Claim(s) withdrawn from consideration:						
AFFIDAVIT OR OTHER EVIDENCE						
<ol> <li>The affidavit or other evidence filed after a final action, but because applicant failed to provide a showing of good an was not earlier presented. See 37 CFR 1.116(e).</li> </ol>						
9. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to showing a good and sufficient reasons why it is necessar	overcome <u>all</u> rejections under appea	al and/or appellant fai	Is to provide a			
10. ☐ The affidavit or other evidence is entered. An explanatio REQUEST FOR RECONSIDERATION/OTHER	n of the status of the claims after e	ntry is below or attach	ed.			
11.   The request for reconsideration has been considered bu See attached sheet	it does NOT place the application in	n condition for allowar	ice because:			
<ul> <li>12. ☐ Note the attached Information Disclosure Statement(s).</li> <li>13. ☐ Other:</li> </ul>	(PTO/SB/08) Paper No(s)					
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Application/Control Number: 10/717,403

Art Unit: 2877

## Advisory Action Continued

## Response to Arguments

1. Applicant's arguments filed 12/12/2007 have been fully considered but they are not persuasive. It appears applicant has misunderstood the view point expressed by examiner in the Final Rejection dated Nara et al. as shown previously, while not explicitly, but rather implicitly shows that prior art methods carry out applicant's method as claimed. In Nara et al. a wafer blank is used before any circuit patterns have been transferred onto it, consisting essentially of a blank canvas. Before the plurality of circuit patterns are transferred onto the wafer, it is obviously or as applicant has claimed it, logically divided into zones which are then used to transfer circuit patterns into each zone. Taking the cited passage from Nara et al. used in section one of the Final Rejection dated 10/19/2007 as included below:

"A semiconductor device is formed by repeating a step of transferring a circuit pattern formed on a photomask to a semiconductor wafer by a lithographing process and an etching process. A state of the process, the presence or absence of generation of a foreign matter (particles), and the like in the manufacturing step of the semiconductor device largely exercise an influence on a manufacturing yield of the semiconductor device. To detect them early or preparatorily, a method of inspecting the circuit pattern of the semiconductor wafer in the manufacturing step of the semiconductor device has conventionally been used." (emphasis added)

Nara et al. discloses inspecting each individual circuit pattern as it is transferred onto the semiconductor wafer, which satisfies the claim limitations as claimed. It appears applicant is giving very narrow weight to the claims as scripted. Nothing in applicant's claimed method precludes the individual detection and analyzing of a wafer on a die by die basis as prior art clearly discloses and clearly shown above in the cited passage from Nara et al.

## Conclusion

2. The Final Rejection dated 10/19/2007 is maintained.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Juan D. Valentin II whose telephone number is (571) 272-2433.

The examiner can normally be reached on Mon.-Fri..

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory J. Toatley, Jr. can be reached on (571) 272-2800 ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/JDVII/ Juan D Valentin II Examiner 2877 JDV December 18, 2007